

Si4800

N-channel enhancement mode field-effect transistor

Rev. 01 — 13 July 2001

Product data

1. Description

N-channel enhancement mode field-effect transistor in a plastic package using TrenchMOS^{TM1} technology.

Product availability:

Si4800 in SOT96-1 (SO8).

2. Features

- Low on-state resistance
- Fast switching
- TrenchMOSTM technology.

3. Applications

- DC to DC convertors
- DC motor control
- Lithium-ion battery applications
- Notebook PC
- Portable equipment applications.

4. Pinning information

Table 1: Pinning - SOT96-1, simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1,2,3	source (s)	0.	d
4	gate (g)	8 <u> </u>	
5,6,7,8	drain (d)	1	g MBB076 S
		SOT96-1 (SO8)	

^{1.} TrenchMOS is a trademark of Royal Philips Electronics.





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5. Quick reference data

Table 2: Quick reference data

Symbol	Parameter	Conditions	Тур	Max	Unit
V_{DS}	drain-source voltage (DC)	T _j = 25 to 150 °C	_	30	V
I _D	drain current	T_{amb} = 25 °C; pulsed; $t_p \le 10$ s	_	9	Α
P _{tot}	total power dissipation	T_{amb} = 25 °C; pulsed; $t_p \le 10$ s	_	2.5	W
Tj	junction temperature		_	150	°C
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 9 \text{ A}; T_j = 25 ^{\circ}\text{C}$	15.5	18.5	$m\Omega$
		$V_{GS} = 4.5 \text{ V}; I_D = 7 \text{ A}; T_j = 25 ^{\circ}\text{C}$	27.5	33	$m\Omega$

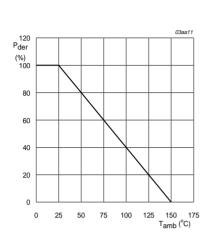
6. Limiting values

Table 3: Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

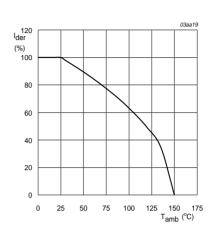
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage (DC)	T _j = 25 to 150 °C	-	30	V
V_{GS}	gate-source voltage (DC)		_	±20	V
I _D	drain current	T_{amb} = 25 °C; pulsed; $t_p \le 10$ s; Figure 2 and 3	_	9	Α
		T_{amb} = 70 °C; pulsed; $t_p \le 10$ s; Figure 2	-	7	Α
I_{DM}	peak drain current	T_{amb} = 25 °C; pulsed; $t_p \le 10 \mu s$; Figure 3	-	40	Α
P _{tot}	total power dissipation	T_{amb} = 25 °C; pulsed; $t_p \le 10$ s; Figure 1	-	2.5	W
		T_{amb} = 70 °C; pulsed; $t_p \le 10$ s; Figure 1	-	1.6	W
T _{stg}	storage temperature		– 55	+150	°C
Tj	operating junction temperature		-55	+150	°C
Source-	drain diode				
I _S	source (diode forward) current	T_{amb} = 25 °C; pulsed; $t_p \le 10 \text{ s}$	-	2.3	Α

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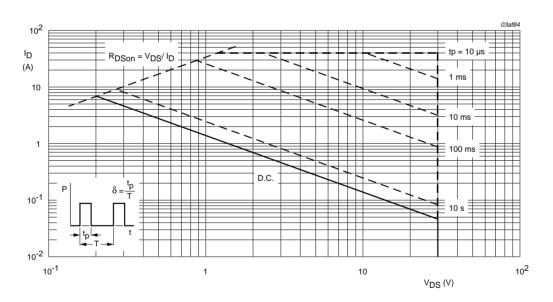
$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 1. Normalized total power dissipation as a function of mounting base temperature.



$$I_{der} = \frac{I_D}{I_{D(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized continuous drain current as a function of mounting base temperature.



T_{amb} = 25 °C; I_{DM} is single pulse.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

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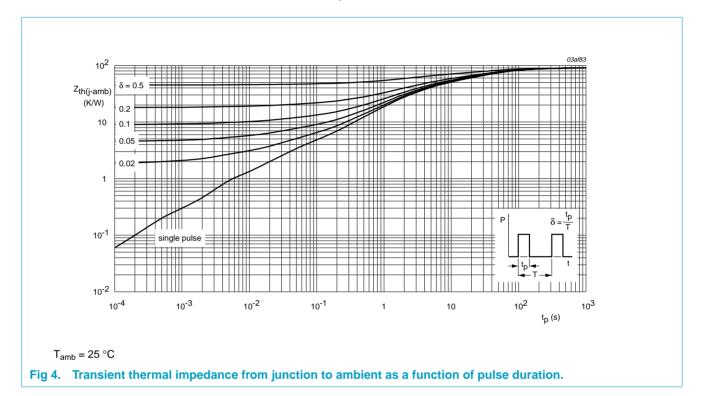
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7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed circuit board; $t_p \le 10 \text{ s}$; minimum footprint; Figure 4	50	K/W

7.1 Transient thermal impedance



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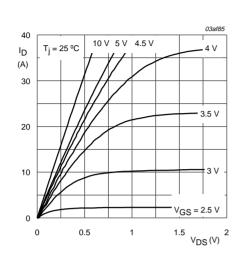
8. Characteristics

Table 5: Characteristics

 $T_i = 25 \,^{\circ}C$ unless otherwise specified

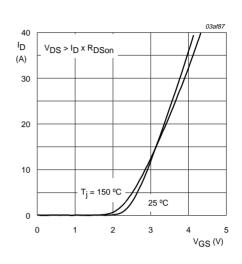
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 ^{\circ}C$	8.0	_	_	V
I _{DSS}	drain-source leakage current	V _{DS} = 24 V; V _{GS} = 0 V				
		T _j = 25 °C	_	_	1	μΑ
		T _j = 55 °C	_	_	5	μΑ
I _{GSS}	gate-source leakage current	$V_{GS} = \pm 20 \text{ V}; V_{DS} = 0 \text{ V}$	_	_	100	nΑ
I _{D(on)}	On-state drain current	V _{DS} ≥ 5; V _{GS} = 10 V	30	_	_	Α
R_{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 9 A; Figure 7 and 8	_	15.5	18.5	$m\Omega$
		$V_{GS} = 4.5 \text{ V}; I_D = 7 \text{ A}; Figure 7 and 8$	_	27.5	33	$m\Omega$
Dynamic	c characteristics					
g _{fs}	forward transconductance	$V_{DS} = 15 \text{ V}; I_D = 9 \text{ A}$	-	19	_	S
$Q_{g(tot)}$	total gate charge	$I_D = 9 \text{ A}$; $V_{DD} = 15 \text{ V}$; $V_{GS} = 5 \text{ V}$; Figure 13	-	19	_	nC
Q_{gs}	gate-source charge		-	4	_	nC
Q_{gd}	gate-drain (Miller) charge		-	7.5	_	nC
t _{d(on)}	turn-on delay time	V_{DD} = 15 V; R_D = 15 Ω ; V_{GS} = 10 V; R_G = 6 Ω	-	11	16	ns
t _r	rise time		-	8	15	ns
t _{d(off)}	turn-off delay time		_	22	30	ns
t _f	fall time		_	9	15	ns
Source-	drain (reverse) diode					
V_{SD}	source-drain (diode forward) voltage	I _S = 2.3A; V _{GS} = 0 V; Figure 12	_	0.7	1.2	V
t _{rr}	reverse recovery time	$I_S = 2.3 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$	_	50	80	ns

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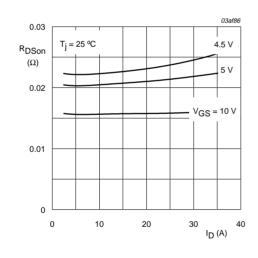
T_i = 25 °C

Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values.



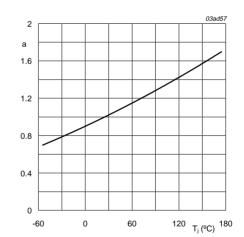
 T_j = 25 °C and 150 °C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values.



 $T_j = 25$ °C





 $a = \frac{R_{DSon}}{R_{DSon}(25^{\circ}C)}$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature.

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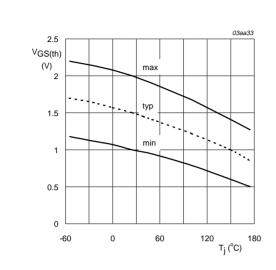
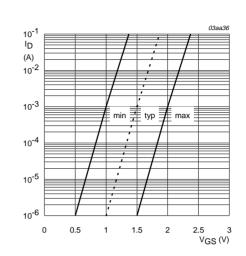
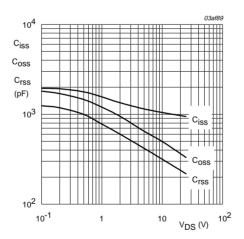


Fig 9. Gate-source threshold voltage as a function of junction temperature.



 $T_{j} = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$

Fig 10. Sub-threshold drain current as a function of gate-source voltage.

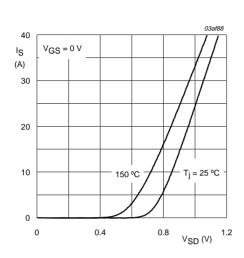


V_{GS} = 0 V; f = 1 MHz

 $I_D = 250 \ \mu A; \ V_{DS} = V_{GS}$

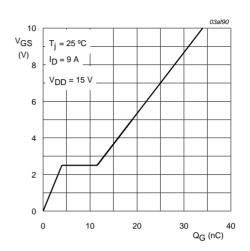
Fig 11. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values.

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 $T_j = 25 \,^{\circ}\text{C}$ and 150 $^{\circ}\text{C}$; $V_{GS} = 0 \,^{\circ}\text{V}$

Fig 12. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values.



 $I_D = 9 A; V_{DD} = 15 V$

Fig 13. Gate-source voltage as a function of gate charge; typical values.

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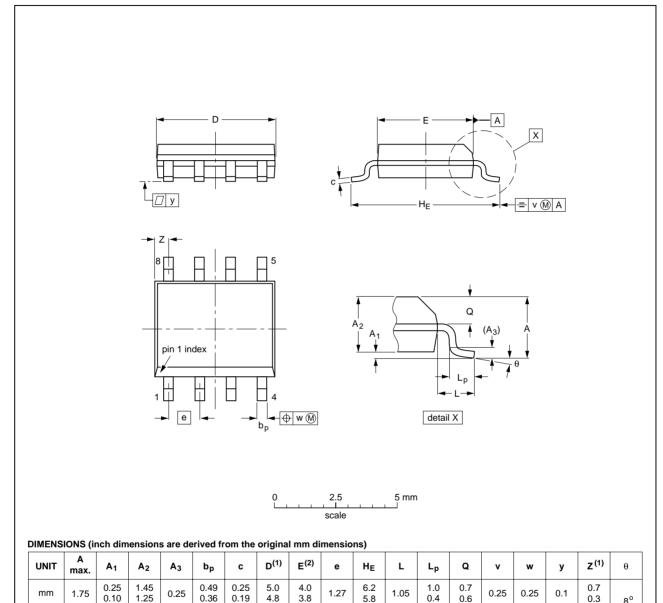
9. Package outline

SO8: plastic small outline package; 8 leads; body width 3.9 mm

SOT96-1

0.028

0.012



Notes

inches

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

0.01

0.019 0.0100

0.014 | 0.0075

0.20

0.19

0.16

0.15

2. Plastic or metal protrusions of 0.25 mm maximum per side are not included.

OUTLINE	REFERENCES			EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	EIAJ		PROJECTION	ISSUE DATE
SOT96-1	076E03S	MS-012AA				95-02-04 97-05-22

0.050

0.244

0.228

0.041

0.039

0.016

0.028

0.024

0.01

0.01

0.004

Fig 14. SOT96-1 (SO8).

0.010

0.004

0.069

0.057

0.049

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10. Revision history

Table 6: Revision history

Rev	Date	CPCN	Description
01	20010713	-	Product specification; initial version

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11. Data sheet status

Data sheet status [1]	Product status [2]	Definition
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
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^[1] Please consult the most recently issued data sheet before initiating or completing a design.

12. Definitions

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Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

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^[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL http://www.semiconductors.philips.com.

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Philips Semiconductors - a worldwide company

Argentina: see South America

Australia: Tel. +61 2 9704 8141, Fax. +61 2 9704 8139 **Austria:** Tel. +43 160 101, Fax. +43 160 101 1210 **Belarus:** Tel. +375 17 220 0733, Fax. +375 17 220 0773

Belgium: see The Netherlands **Brazil:** see South America

Bulgaria: Tel. +359 268 9211, Fax. +359 268 9102

Canada: Tel. +1 800 234 7381

China/Hong Kong: Tel. +852 2 319 7888, Fax. +852 2 319 7700

Colombia: see South America Czech Republic: see Austria

Denmark: Tel. +45 3 288 2636, Fax. +45 3 157 0044 **Finland:** Tel. +358 961 5800, Fax. +358 96 158 0920 **France:** Tel. +33 1 4728 6600, Fax. +33 1 4728 6638 **Germany:** Tel. +49 40 23 5360, Fax. +49 402 353 6300 **Hungary:** Tel. +36 1 382 1700, Fax. +36 1 382 1800 **India:** Tel. +91 22 493 8541, Fax. +91 22 493 8722

Indonesia: see Singapore

Ireland: Tel. +353 17 64 0000, Fax. +353 17 64 0200 Israel: Tel. +972 36 45 0444, Fax. +972 36 49 1007 Italy: Tel. +39 039 203 6838, Fax +39 039 203 6800 Japan: Tel. +81 33 740 5130, Fax. +81 3 3740 5057 Korea: Tel. +82 27 09 1412, Fax. +82 27 09 1415 Malaysia: Tel. +60 37 50 5214, Fax. +60 37 57 4880

Mexico: Tel. +9-5 800 234 7381

Middle East: see Italy

For all other countries apply to: Philips Semiconductors,

Marketing Communications,

Building BE, P.O. Box 218, 5600 MD EINDHOVEN,

The Netherlands, Fax. +31 40 272 4825

Netherlands: Tel. +31 40 278 2785, Fax. +31 40 278 8399 New Zealand: Tel. +64 98 49 4160, Fax. +64 98 49 7811 Norway: Tel. +47 22 74 8000, Fax. +47 22 74 8341 Philippines: Tel. +63 28 16 6380, Fax. +63 28 17 3474 Poland: Tel. +48 22 5710 000, Fax. +48 22 5710 001

Portugal: see Spain **Romania:** see Italy

Russia: Tel. +7 095 755 6918, Fax. +7 095 755 6919 **Singapore:** Tel. +65 350 2538, Fax. +65 251 6500

Slovakia: see Austria **Slovenia:** see Italy

South Africa: Tel. +27 11 471 5401, Fax. +27 11 471 5398 **South America:** Tel. +55 11 821 2333, Fax. +55 11 829 1849

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